Full counting statistics of Andreev tunneling

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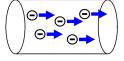
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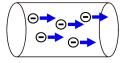
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The full counting statistics (FCS) of charge transfer in nano-electronic circuits provides information about fundamental tunneling processes. ^{1–3} FCS is not limited to normal-state conductors, but may equally well describe charge fluctuations in superconducting structures. Nevertheless, despite considerable theoretical interest in the FCS of superconductors, ^{4–12} experiments have so far been restricted to normal-state electrons. ^{13–23} Here we measure the FCS of Andreev events in which Cooper pairs are either produced from electrons that are reflected as holes at a superconductor/normal-state interface or annihilated in the reverse process. Surprisingly, the FCS consists of quiet periods with no Andreev processes, interrupted by the tunneling of a single electron that triggers an avalanche of Andreev events giving rise to strongly super-Poissonian distributions. Our experiment is important for quantum metrological applications ²⁴ and for entanglement generation using Cooper pair splitters. ^{25–27}

How can we characterize a stream of particles (e.g. an electric current) ?

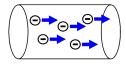


How can we characterize a stream of particles (e.g. an electric current)?



GOOD Average current *I*

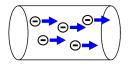
How can we characterize a stream of particles (e.g. an electric current)?



GOOD Average current I

BETTER I + shot noise S_{shot}

How can we characterize a stream of particles (e.g. an electric current)?

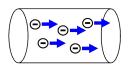


GOOD Average current *I*

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BEST FCS p(n, t)

How can we characterize a stream of particles (e.g. an electric current)?



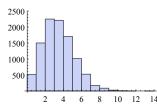
GOOD Average current *I*

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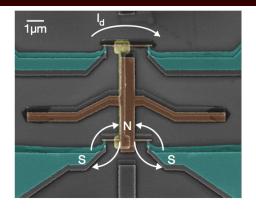
BEST FCS p(n, t)

$$I = \frac{e}{T} \sum_{n} np(n, T)$$

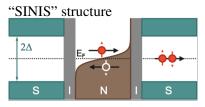
$$S_{\text{shot}} = \frac{e^2}{T} \sum_{n} n^2 p(n, T)$$



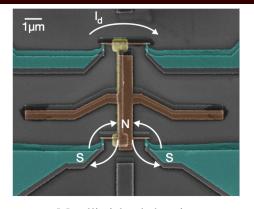
Experimental setup



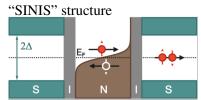
Single-electron transistor (I_d)



Experimental setup



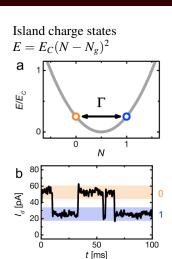
Single-electron transistor (I_d)

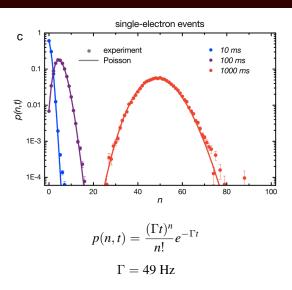


- Metallic island charging energy: $E_C = 40 \mu eV$
- \bullet Superconducting gap (Al) $\Delta = 210~\mu \mathrm{eV}$
- Tunnel resistance $R_T = 490 \text{ k}\Omega$
- Dil. fridge: T = 50 mK

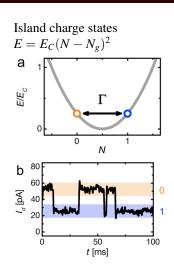
 $E_C < \Delta$ necessary to observe Andreev tunneling processes

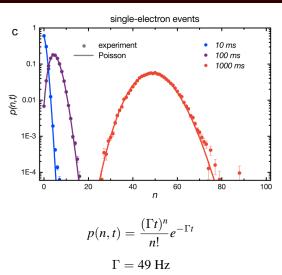
Single-electron events





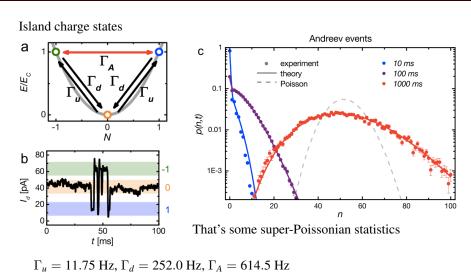
Single-electron events





Poisson distributed events ⇒ independent tunneling events

Andreev processes



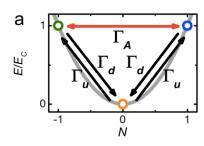
Calculation of the FCS, master equation

Classical description: only keep track of the probability $p_{\alpha}(n,t)$ of having observed n Andreev processes and being in the charge state α at time t

$$\begin{split} \dot{p}_d(n,t) &= -2\Gamma_u\,p_d(n,t) + \Gamma_d\,p_u(n,t) \\ \dot{p}_u(n,t) &= \underbrace{2\Gamma_u\,p_d(n,t) - \Gamma_d\,p_u(n,t)}_{\text{Single-electron processes}} + \underbrace{\Gamma_A(p_u(n-1,t) - p_u(n,t))}_{\text{Andreev processes, change }n} \end{split}$$

$$p_d(n,0) = \delta_{n0} \frac{\Gamma_d}{2\Gamma_u + \Gamma_d}$$
$$p_u(n,0) = \delta_{n0} \frac{2\Gamma_u}{2\Gamma_u + \Gamma_d}$$

Electron temperature $T \approx 140mK$



Calculation of the FCS

FCS: $p(n,t) = \sum_{\alpha} p_{\alpha}(n,t)$

Trick: compute the cumulant generating function

$$S(\chi, t) = \log \left(\sum_{n} e^{i\chi n} p(n, t) \right)$$

Average $\langle n \rangle = -i\partial_\chi \mathcal{S}(\chi,t)|_{\chi=0}$, variance $(\Delta n)^2 = -\partial_\chi^2 \mathcal{S}(\chi,t)|_{\chi=0}$, ...

$$\begin{pmatrix} \dot{p}_u(\chi,t) \\ \dot{p}_d(\chi,t) \end{pmatrix} = \begin{pmatrix} \Gamma_A(e^{i\chi}-1) - \Gamma_d & 2\Gamma_u \\ \Gamma_d & -2\Gamma_u \end{pmatrix} \begin{pmatrix} p_u(\chi,t) \\ p_d(\chi,t) \end{pmatrix}$$

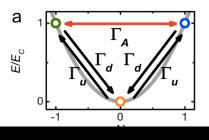
Calculation of the FCS, result

Result

$$\mathcal{S}(\chi,t) = 2\Gamma_u t \sum_{m=1}^{\infty} q(m)(e^{im\chi} - 1) + \underbrace{\mathcal{O}(\Gamma_u^2)}_{\text{correlations between avalanches, small}}$$

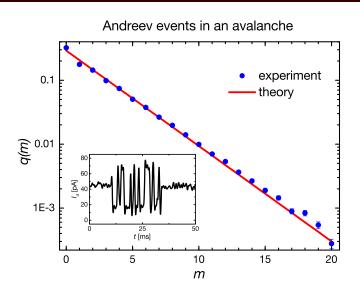
 \Rightarrow sum of independent Poisson processes that with rate $2\Gamma_u$ generate avalanches of m Andreev events with probability q(m)

$$q(m) = \frac{\Gamma_d}{\Gamma_A + \Gamma_d} \left(\frac{\Gamma_A}{\Gamma_A + \Gamma_d} \right)^m.$$



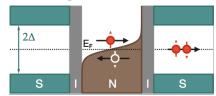
Single-electron tunneling events trigger avanlanches

Avalanche statistics

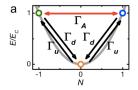


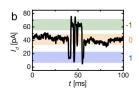
Conclusions

• (First?) FCS of Andreev processes in a SINIS structure



• Super-Poissonian statistics explained by avalanches





• Future: possible applications to Cooper pair splitters; metrology (SINIS turnstile as current standard)